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Optics and photonics — Test methods for telescopic systems —

Part 6: Test methods for veiling glare index

*Optique et photonique — Méthodes d'essai pour systèmes
télescopiques —*

Partie 6: Méthodes d'essai de l'indice de lumière parasite



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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

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The committee responsible for this document is ISO/TC 172, *Optics and photonics*, Subcommittee SC 4, *Telescopic systems*.

This second edition cancels and replaces the first edition (ISO 14490-6:2005), of which it constitutes a minor revision. ISO 14490 consists of the following parts, under the general title *Optics and photonics — Test methods for telescopic systems*:

- *Part 1: Test methods for basic characteristics*
- *Part 2: Test methods for binocular systems*
- *Part 3: Test methods for telescopic sights*
- *Part 4: Test methods for astronomical telescopes*
- *Part 5: Test methods for transmittance*
- *Part 6: Test methods for veiling glare index*
- *Part 7: Test methods for limit of resolution*
- *Part 8: Test methods for night-vision devices*